

Search Notes

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10/805,297

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

WANG ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	133	1/2/2006	HN
330	254	1/2/2006	HN
330	282	1/2/2006	HN
330	86	1/2/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
U.S-PG PUB		1/2/2006	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST UPDATE SEARCH SEE PRINTOUT	1/2/2006	HN